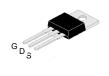






800V N-CHANNEL MOSFET

CD7N80



TO-220



TO-220 Leaded Plastic Package RoHS compliant

FEATURES:

- 1. Fast Switching
- 2. 100% avalanche tested
- 3. Improved dv/dt capability

APPLICATION:

- 1. Switch mode power supply (SMPS)
- 2. Uninterruptible power supply (UPS)
- 3. Power factor correction (PFC)

ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C Unless otherwise specified)

PARAMETERS	SYMBOL	VALUE	UNIT
Drain-Source Voltage (V _{GS} = 0V)	V_{DSS}	800	V
Continuous Drain Current	I_{D}	7	Α
Pulse Drain Current ¹	I _{DM}	24	Α
Gate-Source Voltage	V_{GSS}	±30	V
Single Pulse Avalanche Energy ²	E _{AS}	180	mJ
Avalanche Current ¹	I _{AS}	7	Α
Repetitive Avalanche Energy ¹	E _{AR}	0.72	mJ
Power Dissipation (T _C = 25°C)	P_{D}	45.8	W
Operating Junction & storage Temperature Range	T_J,T_stg	-55 to +150	°C

THERMAL RESISTANCE

Thermal Resistance, Junction-to-Case	R_{thJC}	2.73	°C/W
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62	C/VV







ELECTRICAL CHARACTERISTICS at (Ta = 25 °C Unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TVP	MAY	UNIT
	STWIDUL	1E31 CONDITIONS	IVIIIN	117	IVIAA	UNIT
STATIC CHARACTERISTICS						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	800			V
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 800 \text{V}, V_{GS} = 0 \text{V}, T_{J} = 25 ^{\circ}\text{C}$			1	μΑ
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30$			±100	nΑ
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	3.0		4.0	V
Drain-Source on-Resistance ³	R _{DS(on)}	V_{GS} =10V, I_D =3A		1.65	2.1	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{iss}			833		
Output Capacitance	C _{oss}	V _{GS} =10V,		99		pF
Reverse Transfer Capacitance	C _{rss}	V _{DS} =25V, f=1.0MHz		23		
Gate Resistance	R_{g}			2		Ω
Total Gate Charge	Q_g)/ 040\/ L 04		38		nC
Gate-Source Charge	Q_gs	$V_{DD} = 640 \text{V}, I_D = 6 \text{A},$		4		
Gate-Drain Charge	Q_{gd}	V _{GS} =10A		24.5		
Turn-on delay Time	t _{d(on)}			37		
Turn-on Rise Time	t _r	V_{DD} =400V, I_{D} =6A,		16.5		nS
Turn-off delay Time	$t_{d(off)}$	$R_G=25\Omega$		100		113
Turn-off Fall Time	t _f			32		
DRAIN-SOURCE BODY DIODE CHARACTERISTICS						
Continuous Body Diode Current	I _S	T - 25°C			7	۸
Pulse Diode Forward Current	I _{SM}	$T_C = 25^{\circ}C$			24	Α
Body Diode Voltage	V _{SD}	T_J =25°C, I_{SD} =3A, V_{GS} =0V			1.4	V
Reverse Recovery Time	t _{rr}	V _{DD} =400V, I _S =6A,		510		ns
Reverse Recovery Charge	Q _{rr}	diF/dt=100A/µS		5.2		μC

Note:

- 1. Repetitive rating; pulse width limited by max. junction temperature
- 2. L=10mH, V_{DD} =50V, R_{G} =25 Ω , Starting T_{j} = 25°C
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1%



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TYPICAL CHARACTERISTICS CURVES

Fig. 1: On - State Characteristics

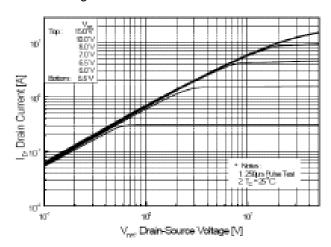


Fig. 4: On - Resistance Variation vs Temperature

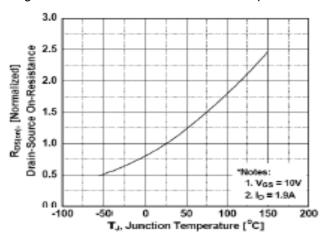


Fig. 2: Transfer Characteristics

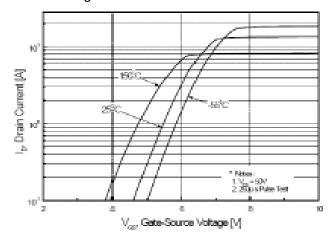


Fig. 5: Capacitance Characteristics

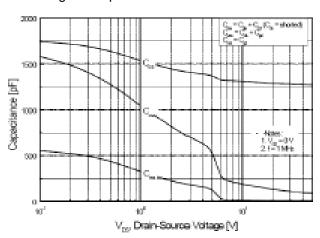


Fig. 3: Breakdown Voltage Variation vs Temperature

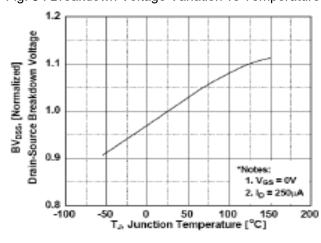
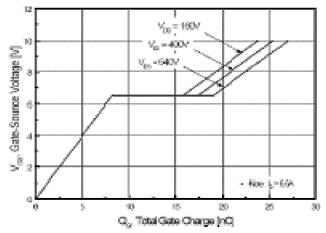


Fig. 5 : Capacitance Characteristics





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TYPICAL CHARACTERISTICS CURVES

Fig. 7: Maximum safe Operating Area

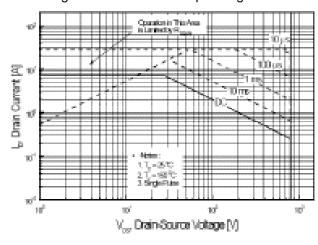


Fig. 8: Maximum Drain Current vs Case Temperature

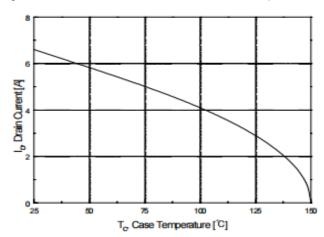
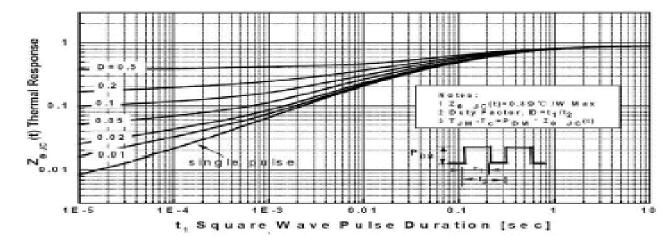


Fig. 9: Transient Thermal Response Curve





Recommended Reflow Solder Profiles

The recommended reflow solder profiles for Pb and Pb-free devices are shown below.

Figure 1 shows the recommended solder profile for devices that have Pb-free terminal plating, and where a Pb-free solder is used.

Figure 2 shows the recommended solder profile for devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with a leaded solder.

Figure 1

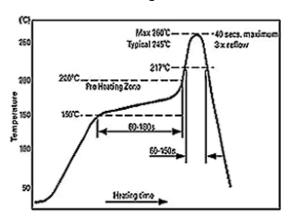
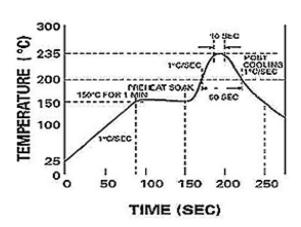


Figure 2



Reflow profiles in tabular form

Profile Feature	Sn-Pb System	Pb-Free System
Average Ramp-Up Rate	~3°C/second	~3°C/second
Preheat – Temperature Range – Time	150-170°C 60-180 seconds	150-200°C 60-180 seconds
Time maintained above: – Temperature – Time	200°C 30-50 seconds	217°C 60-150 seconds
Peak Temperature	235°C	260°C max.
Time within +0 -5°C of actual Peak	10 seconds	40 seconds
Ramp-Down Rate	3°C/second max.	6°C/second max.

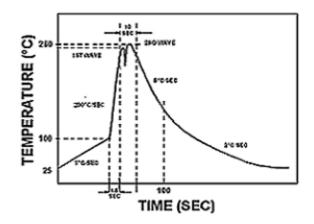




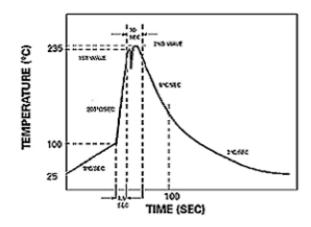


Recommended Wave Solder Profiles

The Recommended solder Profile For Devices with Pb-free terminal plating where a Pb-free solder is used



The Recommended solder Profile For Devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with leaded solder



Wave Profiles in Tabular Form

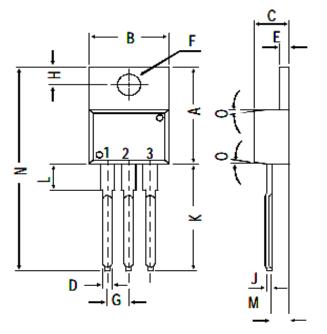
Profile Feature	Sn-Pb System	Pb-Free System	
Average Ramp-Up Rate	~200°C/second	~200°C/second	
Heating rate during preheat	Typical 1-2, Max 4°C/sec	Typical 1-2, Max 4°C/Sec	
Final preheat Temperature	Within 125°C of Solder Temp	Within 125°C of Solder Temp	
Peak Temperature	235°C	260°C max.	
Time within +0 -5°C of actual Peak	10 seconds	10 seconds	
Ramp-Down Rate	5°C/second max.	5°C/second max	





PACKAGE DETAILS

TO-220 Package Outline and Dimension

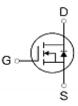


DIM	MIN	MAX
Α	14.42	16.51
В	9.63	10.67
С	3.56	4.83
D		0.90
E	1.15	1.40
F	3.75	3.88
G	2.29	2.79
Н	2.54	3.43
J		0.56
K	12.70	14.73
L	2.80	4.07
М	2.03	2.92
N		31.24
0		7°

All Dimensions are in mm

Pin Configurations

- 1. Gate
- 2. Drain
- 3. Source





Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing supplied by CDIL.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying .
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- · Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- · The product shall not be placed directly on the floor.
- The product shall be stored on a plane area. They should not be turned upside down. They should not be placed against the wall.

Shelf Life of CDIL Products

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

If products are stored longer than the shelf life of 2 years the products shall be subjected to quality check as per CDIL quality procedure.

The products are further warranted for another one year after the date of shipment subject to the above conditions in CDIL original packing.

Floor Life of CDIL Products and MSL Level

When the products are opened from the original packing, the floor life will start.

For this, the following JEDEC table may be referred:

JEDEC MSL Level			
Level	Time	Condition	
1	Unlimited	≤30 °C / 85% RH	
2	1 Year	≤30 °C / 60% RH	
2a	4 Weeks	≤30 °C / 60% RH	
3	168 Hours	≤30 °C / 60% RH	
4	72 Hours	≤30 °C / 60% RH	
5	48 Hours	≤30 °C / 60% RH	
5а	24 Hours	≤30 °C / 60% RH	
6	Time on Label(TOL)	≤30 °C / 60% RH	





Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished in the Data Sheet and on the CDIL Web Site/CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).

CDIL strives for continuous improvement and reserves the right to change the specifications of its products without prior notice.



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